# **VOLUME CONTENTS**

VOLUME 32, NUMBER 1/2	J	AN/FEB 1992 PAGES 1-302
S. G. Chowdhury and K. B. Misra	1	Evaluation of fuzzy reliability of a non-series parallel network
M. N. Gopalan and S. S. Waghmare	5	Cost-benefit analysis of single server $n$ -unit imperfect switch system with delayed repair
M. N. Gopalan and N. Anantharaman	11	Stochastic modelling of a two-stage transfer-line production system with end buffer and random demand
D. K. Pandey, S. M. Gupta and N. K. Jaiswal	17	Reliability analysis of two-unit warm standby system with partial failure mode and inspection time
M. Scherge, V. Breternitz and Ch. Knedlik	21	Simulation of electromigration behaviour in Al metallization of integrated circuits
Den-Jyi Chen and Ming-Cheng Sheng	25	A new recursive algorithm for the reliability evaluation of a distributed program
W. G. Schneeweiss	35	Fault-trees for a voting circuit; synthesis and joint analysis
V. Nicola, A. Bobbio and K. Trivedi	49	A unified performance reliability analysis of a system with a cumulative down time constraint
A. Noore, S. K. Tewksbury and M. Divakurani	67	On optimizing yield reliability and area overhead in large memory arrays
M. M. El-Fahham	79	A note on recursive estimator of the density function which is not necessarily continuous
B. N. Masters, T. O. Lewis and W. J. Kolarik	89	A confidence interval for the availability ratio for systems with Weibull operating time and lognormal repair time
E. Petrova and N. Malevris	101	Rules and criteria for when to stop testing a piece of software
Hoang Pham	119	Optimal design of k-out-of-n redundant systems
Who Kee Chung	127	Reliability analysis of a human operator under different levels of stress
V. N. Rayapati and D. Mukedkhar	133	Ultra high reliable spacecraft computer system design considerations
S. Yanagi	143	An approximation analysis for the availability of a parallel redundant system with general distributions
T. I. Sultan	159	Optimum reliability investment in the electronics industry
A. Scorzoni, G. L. Baldini and C. Caprile	167	Ohmic contact electromigration
W. J. Mee and G. S. Hura	175	Synchronization techniques for distributed systems: an overview
L. Anneberg, G. Rajappan, H. Singh and E. Yaprak	199	Parallel Petri net path searching on a local area network—object oriented Pascal implementation
D. K. Dey and Pei-San Liao Liu	207	On comparison of estimators in a generalized life model
A. H. Rawicz	223	Can a noninvasive reliability prediction of electronic boards be accurate?
A. S. Papadopoulos and R. C. Tiwari	233	Comparison of Bayesian nonparametric estimates of the reliability with rival estimates
S. K. Bhattacharya and R. C. Tiwari	241	Hierarchical Bayesian reliability analysis using Erlang families of priors and hyperpriors

R. Badarinathi and R. C. Tiwari	249	Hierarchical Bayesian approach to reliability estimation under competing risk
A. Kyriakoussis and A. S. Papadopoulos	259	The zero-truncated negative binomial distribution as a failure model from the Bayesian approach
K. K. Govil	265	Technical Notes Optimal maintainability allocation using the geometric programming method
K. K. Govil	267	Fitting maintenance cost vs maintainability data to a standard curve
K. K. Govil	269	A simple model for life cycle cost vs maintainability function
Xianhua Wei	271	Testing whether one distribution is more IFR than another
*	275	Book Review Fundamentals of Manipulator Calibration
	277	Calendar of International Conferences, Symposia, Lectures and Meetings of Interest
	281	Publications, Notices, Calls for Papers, etc.
	283	World Abstracts on Microelectronics and Reliability
VOLUME 32, NUMBER 3		MAR 1992 PAGES 303-452
K. P. Soman and K. B. Misra	303	A least square estimation of three parameters of a Weibull distribution
R. P. Anjard Sr	307	Software quality assurance considerations
L. R. Goel and P. Shrivastava	313	A single unit man-machine system with varying physical conditions of the repairman
S. K. Singh and G. C. Sharma	319	Analysis of a composite performance reliability evaluation for Markovian queueing systems
Lee Gang Soo and Yoon Jung-Mo	323	An empirical study on the complexity metrics of Petri nets
Hong-Zhou Wang, Bao-Hua Ma and Ju-Sheng Shi	331	A research study of environmental factors for the gamma distribution
I. J. Jóźwiak	337	Reliability exploration of microcomputer systems using the Weibull distribution
I. J. Jóźwiak	341	Use of concomitant variables for reliability exploration of micro-computer systems
I. J. Jóźwiak	345	The reliability and functional model of a computer network with a branched structure
R. K. Tuteja and S. C. Malik	351	Reliability and profit analysis of two single-unit models with three modes and different repair policies of repairmen who appear and disappear randomly
J. P. Bhutani and A. Kumar	357	M/G/I queue with rest period
R. Radojcic and P. Giotta	361	Semiconductor device reliability vs process quality
M. W. Hughes, E. Y. DeSoto and Y. S. Sherif	369	On software standards
Y. S. Sherif	407	Software safety analysis: the characteristics of efficient technical walkthroughs
Y. S. Sherif	415	The characteristics of efficient software formal reviews

Y. S. Sherif and J. C. Kelly	423	Improving software quality through formal inspections		
Hoang Pham and D. W. Twigg	433	A note on the Venn and Ben diagrams		
Tongde Guo and Jinhua Cao		Reliability analysis of a multistate one-unit repairable system operating under a changing environment		
	445	Society of Reliability Engineers Bulletin		
	447	Book Review Application Specific Integrated Circuit (ASIC) Technology		
	449	Publications, Notices, Calls for Papers, etc.		
VOLUME 32, NUMBER 4		APR 1992 PAGES 453-600		
D. M. Brkić	453	A method for comparison of pseudo-random number generators		
Hong-zhou Wang, Bao-hua Ma and Ju-sheng Shi	457	Estimation of environmental factors for the normal distribution		
S. G. Chowdhury and K. B. Misra	465	Use of Demorgan's theorem in system reliability studies		
K. P. Soman and K. B. Misra	469	Moments of order statistics using the orthogonal inverse expansion method and its application in reliability		
P. K. Kapur, K. D. Sharma and R. B. Garg	475	Transient solutions of a software reliability model with imperfect debugging and error generation		
M. N. Gopalan and D. Kar	479	Analysis of two-stage transfer-line production system subject to inter-stage inspection and arbitrary arrival and processing time distributions		
I. J. Jóźwiak	483	The influence of the number of users on the reliability of a branched computer network		
I. J. Jóźwiak	487	7 The influence of error occurrence on branched computer net reliability		
K. K. Sharma and R. K. Bhutani	493	A comparison of classical and Bayes risks when the quality varies randomly		
M. C. Rander, A. Kumar and R. K. Tuteja	497	Analysis of a two-unit cold standby system with imperfect assistant repairman and perfect master repairman		
L. R. Goel and V. K. Tyagi	503	A two-unit cold standby system with allowed down-time and correlated failures and repairs		
K. Mohandas, D. Chaudhuri and B. V. A. Rao	509	Optimal periodic replacement with inspection and minimal repair for a system which is inoperable during inspection periods		
A. Srivastava	515	Performance study of <i>n</i> -MOS natural transistor fabricated by low thermal budget process		
Yiu-Wing Leung	525	Reliability and cost of fault tolerant multiprocessing networks with heterogeneous nodes		
M. Dohnal	539	Rough sets in reliability engineering		
T. Giebel and K. Goser	545	A simple, analytical model for hot-carrier induced degradation in n-channel MOSFETs		
M. Yamashiro, M. Satoh and Y. Yuasa	557	quad configuration systems		
B. S. Dhillon and N. Yang	561	common-cause failures and human errors		
C. A. Ntuen	577	Technical Note A note on determining optimum shape parameter for gamma distribution based on the number of system shocks		
		91		

- 581 Publications, Notices, Calls for Papers, etc
- 583 World Abstracts on Microelectronics and Reliability
- 599 Corrigendum

VOLUME 32, NUMBER 5		MAY 1992	PAGES 601-754
J. Singh and B. Dayal	601	Reliability analysis of a system	m in a fluctuating environment
Xianhua Wei	605	Test against a change in NBU	E trends with change-point unknown
Xianhua Wei	607	Test exponentiality against a based on TTT transformation	monotone hazard function alternative
M. Yamashiro, M. Satoh and Y. Yuasa	611	Parallel-series and series-para units having two kinds of fai	allel redundant systems consisting of lure rates
A. A. Chernyshev and A.G. Suchorukov	615	Physical aspects and a metho- when affected by destabilizing	d for evaluating CMOS IC workability ag factors
A. K. Hosni	617	Optimal smoothing parameter under an autoregressive dependent	er of Fourier series density estimates endence model
M. Triantafyllou and A. Leone	621	Electromigration reliability ever process	aluation for a three-level metallization
E. Haupt and H. Schäbe	633	A new model for a lifetime dis rate	stribution with bathtub shaped failure
N. Singh	641	Representation of reliability- autoregressive models	decay processes by time-dependent
Shey-Huei Sheu and Ching-Tien Liou	649	Optimal replacement of a k-	out-of-n system subject to shocks
Shey-Huei Sheu	657	A general replacement of a s	system subject to shocks
Z. Stamenković and N. Stojadinović	663	Chip yield modeling related	to photolithographic defects
K. C. Madan	669	A bulk queueing system with	random failures and two phase repairs
Hong-zhou Wang, Bao-hua Ma and Ju-sheng Shi	679	Estimation of environmental	factors for the log normal distribution
M. Suliman and C. A. Goben	687	Markov availability models of	on neural networks
Yiu-Wing Leung	699	Software reliability growth n	nodel with debugging efforts
R. O. Al-Seedy	705	The service Erlangian machin	ne interference with balking
Hoang Pham	711	Optimal system-profit design	n of k-to-/-out-of-n systems
B. S. Dhillon	719	Failure modes and effects ar	nalysis—bibliography
D. K. Manna	733	Technical Note A note on a paper by Gupta	a and Kumar
	737		eaning Electronics Assemblies
		Foundations for Microstrip	Circuit Design
		Mental Models and Human	-Computer Interaction1
		Mental Models and Human	-Computer Interaction—2
		Reliability - Centered Mainte Methods	nance: Management and Engineering

### Human Factors in Product Design

# Network Reliability and Algebraic Structures

- 747 Calendar of International Conferences, Symposia, Lectures and Meetings of Interest
- 751 Publications, Notices, Calls for Papers, etc.

VOLUME 32, NUMBER 6		JUNE 1992 PAGES 755–900
G. C. Mishra and B. N. Pandey	755	A weighted estimator for the scale parameter of an exponential distribution
F. Guess, E. Walker and D. Gallant	759	Burn-in to improve which measure of reliability?
M. A. W. Mahmoud, M. M. Mohie El-Din and M. E. Moshref	763	Reliability of a reparable system with preventive maintenance and imperfect switch
Z. D. Prijić, S. S. Dimitrijev and N. D. Stojadinović	769	The determination of zero temperature coefficient point in CMOS transistors
L. R. Goel, P. K. Tyagi and Rakesh Gupta	775	Cost analysis of a two-unit chargeable standby system with inter- changeable units and two types of failure
L. R. Goel, Rakesh Gupta and V. S. Rana	781	Stochastic analysis of a xenix operating computer system with two down modes
L. R. Goel and P. Shrivastava	793	A warm standby redundant system with correlated failures and repairs
S. E. Moafi B., L. R. Goel and Rakesh Gupta	799	A stochastic model of a system with two phases of operation
Miss Sharda and Prem Chand Garg	805	Time-dependent queueing model having heterogeneous servers
E. J. Vanderperre	811	Asymptotic behaviour of a multiple parallel system attended by a multiple repairstation
T. Hidaka	817	Approximated reliability of $r$ -out-of- $n(F)$ system with common cause failure and maintenance
K. K. Aggarwal and Yogesh Singh	833	Ascertaining the value of reliability for a software package before release
Young Ho Chun and Chang Shin Lee	839	Optimal replacement policy for a warrantied system with imperfect preventive maintenance operations
Hoang Pham and Hanh K. Phan	845	Mean life of k-to-l-out-of-n systems with nonidentical Weibul! distribution components
M. M. Alidrisi	851	The reliability of a dynamic warm standby redundant system of $\boldsymbol{n}$ components with imperfect switching
C. Constantinescu	861	Analyzing the effect of permanent, intermittent and transient faults on a gracefully degrading microcomputer
M. Dohnal	867	Reliability knowledge and fractal evaluation of chaos
J. Sztrik	875	Asymptotic analysis of a heterogeneous renewable complex system with random environments
E. A. Weis, E. Kinsbron, M. M. Snyder, B. Vogel and N. Croitoru	887	7 Electromigration behavior analysis of aluminum alloys thin film conductors using maximum likelihood methods

<b>VOLUME</b>	32,	NUMBER	7
---------------	-----	--------	---

# **JULY 1992**

PAGES 901-1050

R. K. Agnihotri, Govind Singhal and S. K. Khandelwal	901	Stochastic analysis of a two-unit redundant system with two types of failure
V. Sridharan	905	Optimum planned policies with minimal repair and random lead times
S. Kal	911	Steady state and transient analysis of SFIIL
S. D. Sharma and K. S. Basati	917	A queueing system with alternate batch service
S. A. Siddiqui and M. Subharwal	923	The Mukherjee-Islam failure model
Yow-mow Chen, T. Fujisawa and H. Ōsawa	925	Availability for a $2/3$ :G subsystem and secondary subsystem subject to shut-off rules
Hong-zhou Wang, Bao-hua Ma and Ju-sheng Shi	931	Estimation of environmental factors for the inverse Gaussian distribution
J. C. Chan	935	An investigation of the information contained in faulty signatures
U. Hilleringmann and K. Goser	941	Stacked CMOS circuits integrated in laser-recrystallized silicon films
A. Csenki	945	Sojourn times in Markov processes for power transmission dependability assessment with MatLab
R. M. Patrikar and R. Lal	961	New method for assessing dielectric integrity of MOS oxides
D. J. Klinger	987	Failure time and rate constant of degradation: an argument for the inverse relationship
Shey-Huei Sheu, Ching-Tien Liou and Bee-Ching Tseng	995	Optimal ordering policies and optimal number of minimal repairs before replacement
A. Scott and T. Downs	1003	Some observations on a software reliability model
M. Dohnal	1015	Revitalization of primary reliability knowledge
S. O. Agbo, P. S. Neelakanta and L. M. Lay	1029	Reliability assessment of CCDs operating under ionizing radiation ambients: failure-simulation studies via electrical overstressing
H. Reiche	1043	Society of Reliability Engineers Bulletin
	1045	Book Reviews Assurance Technologies, Principles and Practices
		Reliability by Design. CAE Techniques for Electronic Components and Systems
	1049	Publications, Notices, Calls for Papers, etc.

VOLUME 32, NUMBER 8		AUG 1992 PAGES 1051–1198
E. J. Vanderperre	1051	Reliability of a space shuttle subject to space erosion
Yow-mow Chen, T. Fujisawa and H. Ōsawa	1053	Availability and reliability of the system with pre-emptive priorities and shut-off rules
HB. Bemmann	1063	Application of the hierarchical fault model to reliability considerations
M. A. Aziz, M. A. Sobhan and M. A. Samad	1067	Reduction of computations in enumeration of terminal and multiterminal pathsets by the method of indexing
S. D. Sharma and K. S. Basati	1073	Stochastic model of k-parallel service channels
V. Sridharan	1079	Cost analysis for two-unit warm standby systems

R. P. Kaushal, N. Chammas and 1083 A new formulation for state equation representation for Petri nets H. Singh G. S. Mokaddis, S. W. Labib and 1091 The analysis of a three-phase queueing servicing system with E. A. Soliman renewable servers Shey-Huei Sheu and Ching-Tien Liou 1105 An ordering policy with age-dependent minimal repair and agedependent random repair costs B. S. Dhillon 1115 Reliability testing: bibliography B. S. Dhillon and O. C. Anude 1137 Mining equipment reliability: a review M. Dohnal 1157 Ignorance and uncertainty in reliability reasoning K.-H. Wang and B. D. Sivazlian 1171 Cost analysis of the M/M/R machine repair problem with spares operating under variable service rates F. Beichelt 1185 A general maintenance model and its application to repair limit replacement policies 1197 Society of Reliability Engineers Bulletin **VOLUME 32, NUMBER 9 SEPT 1992** PAGES 1199-1348 M. C. Rander, A. Kumar and 1199 A two-unit cold standby system with major and minor failures and R. K. Tuteja preparation time in the case of major failure R. T. Arora and R. K. Tuteja 1205 Stochastic analysis of an Erlangian arrival with linear cost structure 1215 An empirical study on complexity metrics of Petri nets Gang Soo Lee and Jung-mo Yoon V. Jayabalan and D. Chaudhuri 1223 Sequential imperfect preventative maintenance policies: a case J. M. Kontoleon 1231 The reliability modelling of RAM/ROM fault tolerant memories Tongde Guo and Jinhua Cao 1237 Reliability analysis of a two-unit redundant system with a replaceable repair facility 1241 Note on MTBF versus mean-wear-life versus Mil-Hdbk-217 D. Badenius 1243 Reliability analysis and redundancy optimisation of a multimodular L. R. Goel and Preeti Shrivastava fault tolerant system M. O. Abou El-Ata 1251 An interarrival hyperexponential machine interference with balking and reneging 1257 Availability for 2/n:F and secondary subsystems with general Yow-mow Chen, T. Fujisawa and repair-time distributions and shut-off rules H. Ōsawa Parametric empirical Bayes approach to reliability analysis for the Ravindra K. Tyagi, S. Kumar, 1271 R. C. Tiwari and S. K. Bhattacharaya geometric life model 1283 An age replacement policy with minimal repair and general random Shey-Huei Sheu and Ching-Tien Liou repair cost 1291 Generation of vertex and edge cutsets V. C. Prasad, V. Sankar and K. S. Prakasa Rao 1311 Fuzzy reliability modelling-linguistic approach V. Ramachandran. V. Sankaranarayanan and S. Seshasayee 1319 Relative mean residual life: theory and related topics Xianhua Wei 1327 Calendar of International Conferences, Symposia, Lectures and Meetings of Interest 1331 World Abstracts on Microelectronics and Reliability

VOLUE	AE	22	NUMBER	10
VOLUI	VIE.	34.	NUMBER	10

# OCT 1992

### PAGES 1349-1496

VOLUME 32, NUMBER 10		001 1//2
J. H. Huang	1349	A study of failure of SMT solder joints under thermal cycles by statistics
R. K. Tuteja and G. Taneja	1353	Cost-benefit analysis of a two-server, two-unit, warm standby system with different types of failure
L. R. Goel and P. Shrivastava	1361	Transient analysis of a multiple-unit redundant system
L. R. Goel and V. K. Tyagi	1367	A two unit priority redundant system with three modes and correlated failures and repairs
Lien Zhao-Tung	1373	Reliability analysis of a repairable system in a randomly changing environment
J. C. Chan and B. F. Womack	1379	On the relation of errors and its syndrome in signature analysis
S. A. Salem	1385	Bayesian estimation of a non-linear failure rate from censored samples type II
M. O. Abou-El-Ata and A. I. Shawky	1389	The single-server Markovian overflow queue with balking, reneging and an additional server for longer queues
Who Kee Chung	1395	A reliability analysis of a $k$ -out-of- $N$ : G redundant system with the presence of chance common-cause shock failures
H. H. Liu, W. T. Yang and C. C. Liu	1401	An improved Boolean algebra method for computing the network reliability
O. Martynenko	1421	Some possibilities of restoration organization selection for complex radioelectronic systems
R. K. Agnihotri, G. Singhal and S. K. Khandelwal	1431	Two-unit redundant system with random shocks and inspection
S. K. Singh, R. P. Singh and R. B. Singh	1443	MTTF and availability evaluation of a two unit, three state redundant system with a proviso of random activation
S. A. Siddiqui, Balkrishan, S. Gupta and M. Subharwal	1453	A finite range failure model
Dilip Roy and R. P. Gupta	1459	Classifications of discrete lives
T. S. Uma Maheswari, A. Rekha and A. C. N. Raghava Char	1475	Technical Notes Reliability of single strength under n-stresses
K. K. Sharma and R. K. Bhutani	1479	Non-parametric estimation of sample size and censoring time in life testing experiments
R. Bhandari	1483	On distribution of cycles in a Markovian queueing system
	1489	Book Reviews What Every Engineer Should Know About Microcomputers Hardware/Software Design—A Step-by-Step Example
		Process Improvement in the Electronics Industry
		Contamination Effects on Electronic Products
	1493	Publications, Notices, Calls for Papers, etc.

VOLUME 32, NUMBER 11

NOV 1992

PAGES 1497-1656

# RELIABILITY PHYSICS OF ADVANCED ELECTRON DEVICES

N. Stojadinović 1497 Editorial

W. H. Krautschneider, H. Terletzki 1499 Reliability problems of submicron MOS transistors and circuits and Qin Wang

J. A. Segura, J. Figueras 1509 Approach to the analysis of gate oxide shorts in CMOS digital and A. Rubio circuits C. Bergonzoni, G. Dalla Libera, 1515 Dynamic hot carrier degradation effects in CMOS submicron R. Benecchi and A. Nannini transistors K. P. Rodbell 1521 Electromigration behavior of multilayered AI/Hf and AI/Ti fine lines and its dependence on Cu and Pd solute additions 1527 Techniques and characterization of pulsed electromigration at the J. S. Suehle and H. A. Schafft wafer-level H. Kitagawa, S. Murata. 1533 Single bit failure mechanism in DRAMs caused by MILO cracks J. Nagai, S. Kuroda, M. Amagai, Y. Imamura, M. Itoh and S. Hasegawa F. Corsi, S. Martino, C. Marzocca, 1539 Critical areas for finite length conductors R. Tangorra, C. Baroni and M. Buraschi N. Maene, J. Vandenbroeck and 1545 On-chip electrostatic discharge protections in advanced CMOS K. Allaert technologies S. Graffi, Zs. M. V.-Kovács, 1551 EMI-induced failures in integrated circuit operational amplifiers G. Masetti and D. Golzio F. Fantini and F. Magistrali 1559 Reliability of compound semiconductor devices 1571 Long term degradation of GaAs integrated circuits A. Konttinen and J. Leino P. C. Conti, L. Marchisio 1577 Performances and reliability of HEMTs: state of the art and experand G. Clerico Titinet imental analysis B. Kovács, R. Veresegyházy, 1585 An advanced MESFET burn-in method and equipment I. Mojzes, K. Kazi, F. Csányi, I. Szűcs, A. Sonkoly, I. Házman, I. Deák, I. Menyhárt and Z. Horváth 1589 VLSI failure analysis: a review K. Nikawa G. A. Azzini, G. Arman and 1599 The scanning optical microscope: a powerful tool for failure analysis P. Montangero of electronic devices 1605 Test method in voltage contrast mode using liquid crystals B. Picart and S. Diez Minguez 1615 Multiple adjacent image processing for automated failure location D. Conard, J. D. Russell, J. Laurent, using electron beam testing A. Skaf and B. Courtois F. Grabowski and E. Stolarski 1621 A complementarity of the 1/f noise and the charge-pumping methods for determination of the degradation of the small size MOS transistors 1627 Low-frequency noise measurements as a complementary tool in A. Diligenti, B. Neri and R. Saletti the investigation of integrated circuit reliability A. Bossche 1633 On-chip stress, metal deformation and moisture measurements A. Motta and R. Gussoni 1639 Reliability monitoring of components for telecom applications: failure mechanisms driving technology assessment J. Y. Boulaire, J.-P. Mercier, 1645 Technological analysis of integrated circuits as a part of a manufac-C. Patrac and D. Riviere turing lines agreement for France Telecom: methodology and examples of potential reliability problems 1651 New aspects of the reliability of lithium thyonil chloride cells T. I. Băjenescu 1655 Publications, Notices, Calls for Papers, etc.

VOLUME 32, NUMBER 12		DEC 1992	PAGES 1657-1800
S. D. Sharma and Satya Bhushan	1657		a non-Markovian time-dependent intertransition time distribution
Y. V. S. Sarma	1663	A G   M   M system with M   M repair facility	switch and orientation time for the
A. H. El-Mawaziny	1667		e reliability of series systems with ial time to failure distributions
M. N. Gopalan, K. S. Bhanu and N. N. Murulidhar	1675	Cost analysis of a two-unit repreventive maintenance and/o	repairable system subject to on-line or repair
M. N. Gopalan and S. V. Simhan	1681	Analysis of monitoring policie	es
L. R. Goel and P. Shrivastava	1687	A two-unit standby system maintenance and correlated for	with imperfect switch, preventive ailures and repairs
M. O. Abou El-Ata and K. A. M. Kotb	1693		rate for the queue: M/M/1/N with ng barrier, reneging and an additional
B. S. Dhillon and N. Yang	1699	Stochastic analysis of standby and human errors	systems with common-cause failures
R. Gupta and A. Chaudhary	1713	A two-unit priority standby s Releigh failure-time distribution	ystem subject to random shocks and on
H. Ratschek and J. Rokne	1725	The transistor modeling prob	lem again
S. S. Elias and M. Y. Haggag	1741		t analysis of a three-state parallel system under critical human failures
S. Yamada, J. Hishitani and S. Osaka	1763	Software reliability measurements homogeneous Poisson process	nent and assessment based on non- ss models: a survey
	1775	Book Reviews Software Reliability Handbook	ok
		Assembling and Troubleshoo	ting Microcomputers
		Electronic Equipment Packag	ing Technology
Hans Reiche	1779	Society of Reliability Engine	ers Bulletin
	1781	World Abstracts on Microele	ctronics and Reliability
	i	Title Section, Volume, Cont. 1992	ents and Author Index, Volume 32,

